

Search Notes

Application/Control No.

10/785,153

Examiner

Seung H. Lee

Applicant(s)/Patent under
Reexamination

ISHIKAWA ET AL.

Art Unit

2876

SEARCHED

Class	Subclass	Date	Examiner
235	376	3/5/2006	SHL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Same as	Above	3/5/2006	SHL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
235/383, 385 (see printouts)	3/5/2006	SHL
707/1, 101 (see printouts)	3/5/2006	SHL
705/28 (see printouts)	3/5/2006	SHL
PCT citees	3/5/2006	SHL